

<b>Notice of References Cited</b>	Application/Control No. 10/673,909	Applicant(s)/Patent Under Reexamination HECKMEIER ET AL.	
	Examiner Shean C. Wu	Art Unit 1756	Page 1 of 1

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	B	US-6,890,607	05-2005	Heckmeier et al.	428/1.1
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	M	US-			

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**NON-PATENT DOCUMENTS**

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	U	English translation by computer for JP 10-251186, <a href="http://www4.ipdl.ncipi.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=H10-251186">http://www4.ipdl.ncipi.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=H10-251186</a>
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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